Docket No. 243329US2

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Kenichi KADOTA

SERIAL NO: New Application GAU:

FILED: Herewith EXAMINER:

FOR: SYSTEM FOR, METHOD OF AND COMPUTER PROGRAM PRODUCT FOR DETECTING FAILURE OF

MANUFACTURING APPARATUSES

## INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR

Applicant(s) wish to disclose the following information.

#### REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

#### **RELATED CASES**

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

#### CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

### **DEPOSIT ACCOUNT**

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Marvin J. Spivak

Registration No. 24,913

C. Irvin McClelland
Registration Number 21,124

Customer Number

22850

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 05/03) Docket No.

243329US2

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DOCKET NO: 243329US2 Sheet <u>1</u> of <u>1</u>

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# **STATEMENT OF RELEVANCY**

# Reference AO (JP 2002-323924) on Form PTO- 1449:

Time tendency of yield is adjusted by linear regression method.

(Fig 4 ~ Fig 6. paragraph 7)

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(Modified)		PATENT AND TRAD	EMARK OFFICE	243329US2		New Application		
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				FILING DATE		GROUP		
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	AZ				Additional References sheet(s) attached			
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*Examiner: I	Initial if	reference is considered	, whether or n	ot citation is in conformance with MPEP	609; Draw		h citation if no	ot in
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